TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type (U-MOS V-H)

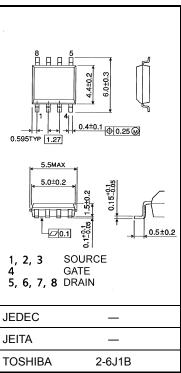
# TPC8032-H

High-Efficiency DC/DC Converter Applications Notebook PC Applications Portable Equipment Applications

- Small footprint due to a small and thin package
- High-speed switching
- Small gate charge: QSW = 8.4 nC (typ.)
- Low drain-source ON-resistance:  $R_{DS}$  (ON) = 5.0 m $\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 60 \text{ S (typ.)}$
- Low leakage current:  $I_{DSS} = 10 \ \mu A \ (max) \ (V_{DS} = 30 \ V)$
- Enhancement mode:  $V_{th}$  = 1.5 to 2.5 V (V<sub>DS</sub> = 10 V, I<sub>D</sub> = 1 mA)

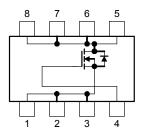
#### Absolute Maximum Ratings (Ta = 25°C)

Characte	eristic	Symbol	Rating	Unit
Drain-source voltage		V <sub>DSS</sub>	30	V
Drain-gate voltage (R	$R_{GS} = 20 \text{ k}\Omega$ )	V <sub>DGR</sub>	30	V
Gate-source voltage		V <sub>GSS</sub>	±20	V
Drain current	DC (Note 1)	I <sub>D</sub>	15	А
Drain current	Pulsed (Note 1)	I <sub>DP</sub>	60	
Drain power dissipati	on (t = 10 s) (Note 2a)	PD	1.9	w
Drain power dissipati		PD	1.0	w
Single-pulse avalance	he energy (Note 3)	E <sub>AS</sub>	146	mJ
Avalanche current		I <sub>AR</sub>	15	А
Repetitive avalanche	energy Note 2a) (Note 4)	E <sub>AR</sub>	0.12	mJ
Channel temperature		T <sub>ch</sub>	150	°C
Storage temperature range		T <sub>stg</sub>	–55 to 150	°C



Weight: 0.085 g (typ.)

### **Circuit Configuration**



Note 1, Note 2, Note 3 and Note 4: See the next page.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

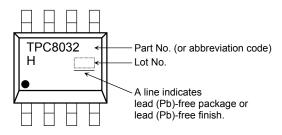
This transistor is an electrostatic-sensitive device. Handle with care.

Unit: mm

#### **Thermal Characteristics**

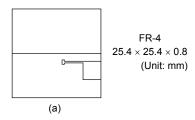
Characteristic	Symbol	Max	Unit	
Thermal resistance, channel to ambient (t = 10 s) (Note 2a)	R <sub>th (ch-a)</sub>	65.8	°C/W	
Thermal resistance, channel to ambient (t = 10 s) (Note 2b)	R <sub>th (ch-a)</sub>	125	°C/W	

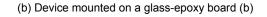
#### Marking (Note 5)

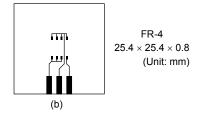


Note 1: The channel temperature should not exceed  $150^{\circ}\mathrm{C}$  during use.

Note 2: (a) Device mounted on a glass-epoxy board (a)







Note 3:  $V_{DD} = 24$  V,  $T_{ch} = 25^{\circ}C$  (initial), L = 500  $\mu$  H, R<sub>G</sub> = 25  $\Omega$ , I<sub>AR</sub> = 15 A

Note 4: Repetitive rating: pulse width limited by max channel temperature

Note 5: \* Weekly code: (Three digits)



Week of manufacture \_ (01 for first week of year, continuing up to 52 or 53) <sup>—</sup> Year of manufacture

(The last digit of the calendar year)

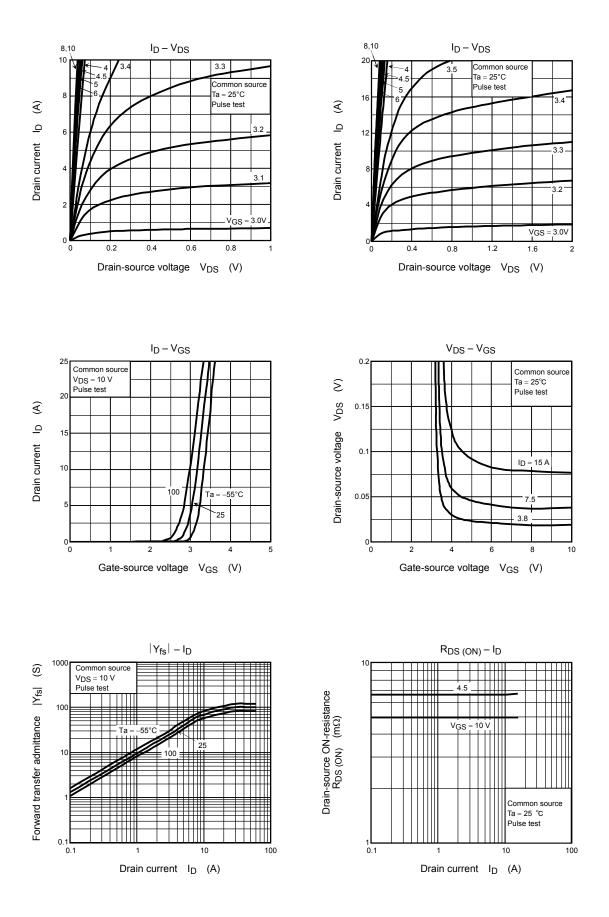
## **Electrical Characteristics (Ta = 25°C)**

Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS}=\pm 20~V,~V_{DS}=0~V$	_		±100	nA
Drain cutoff curre	nt	I <sub>DSS</sub>	$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	_	—	10	μA
	akdown voltago	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	30	_		V
Drain-source brea	rain-source breakdown voltage		$I_D = 10 \text{ mA}, V_{GS} = -20 \text{ V}$	15	_		v
Gate threshold vo	oltage	V <sub>th</sub>	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ mA}$	1.5	_	2.5	V
Drain-source ON	radiatanaa	Dec (cu)	$V_{GS} = 4.5 \text{ V}, I_D = 7.5 \text{ A}$	_	6.6	8.6	mΩ
Diam-source ON-	resistance	R <sub>DS</sub> (ON)	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 7.5 \text{ A}$	_	5.0	6.5	
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 7.5 \text{ A}$	30	60	_	S
Input capacitance	)	C <sub>iss</sub>		_	2270	2846	pF
Reverse transfer	capacitance	C <sub>rss</sub>	$V_{DS} = 10 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$	_	135	205	
Output capacitan	се	C <sub>oss</sub>		_	505	_	
Gate resistance	rg $V_{DS} = 10 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f} = 5 \text{ V}$		$V_{DS} = 10 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f} = 5 \text{ MHz}$		1.0	1.5	Ω
Switching time	Rise time	tr	$V_{GS} \stackrel{10}{}_{0}V \prod_{V \in S} I_{D} = 7.5 \text{ A}$		4	_	ns
	Turn-on time	t <sub>on</sub>		_	12	_	
	Fall time	t <sub>f</sub>			11	_	
	Turn-off time	t <sub>off</sub>	$V_{DD}\simeq 15~V \label{eq:VDD}$ Duty $\leq$ 1%, $t_W=10~\mu s$		37	_	
Total gate charge		0	$V_{DD}\simeq 24~V,~V_{GS}=10~V,~I_{D}=15~A$		33		
(gate-source plus	gate-drain)	Qg	$V_{DD}\simeq 24~V,~V_{GS}=5~V,~I_{D}=15~A$	5A — 17 —			
Gate-source charge 1		Q <sub>gs1</sub>	$V_{DD}\simeq 24~V,~V_{GS}=10~V,~I_{D}=15~A$		7.9		nC
Gate-drain ("Miller") charge		Q <sub>gd</sub>			5.2		-
Gate switch charge		QSW			8.4		

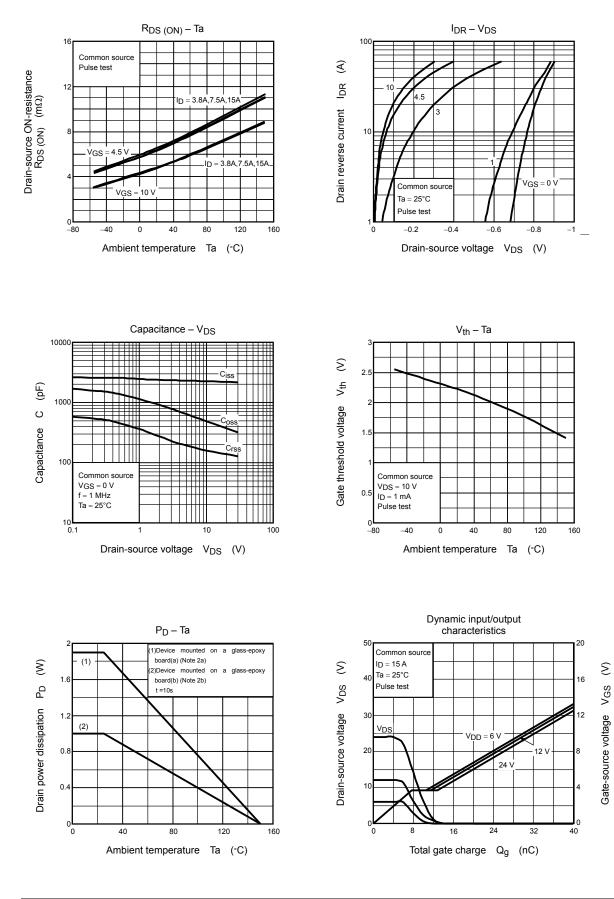
### Source-Drain Ratings and Characteristics (Ta = 25°C)

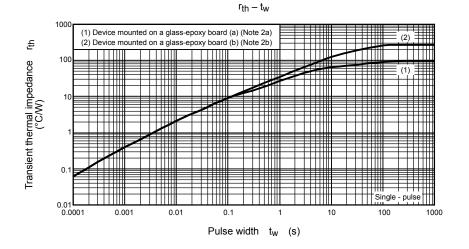
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit	
Drain reverse current	Pulse	(Note 1)	I <sub>DRP</sub>	—	_	_	60	А
Forward voltage (diode)			V <sub>DSF</sub>	$I_{DR} = 15 \text{ A}, \text{ V}_{GS} = 0 \text{ V}$	_		-1.2	V

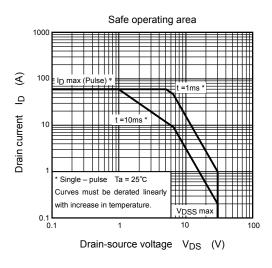
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